



7/19/2012

RELIABILITY MONITOR REPORT
FOR

MFN Complementary BiCMOS (CB50)

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX3643ETG+	MAX3646ETG+
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The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 3274 QUANTITY: 80 FAILS: 0 FITS: 34.9

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 7/1/2011 and 6/30/2012 .

Process Information:

Process Description: MFN Complementary BiCMOS (CB50)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1113	MAX3643ETG+	135C	192 HRS	48	0	J0UZB4001BQ
HIGH TEMP OP LIFE	1113	MAX3643ETG+	135C	240 HRS	32	0	J0UZB4001CQ
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1152	MAX3646ETG+	-65C TO 150C	1000 CYS	77	0	JJR0J3056BC
TEMP CYCLE, 5' RAMP, 10' DWELL	1152	MAX3646ETG+	-65C TO 150C	1000 CYS	77	0	JJR0J3056BA
TEMP CYCLE, 5' RAMP, 10' DWELL	1208	MAX3646ETG+	-65C TO 150C	1000 CYS	77	0	JJR0J3046
TEMP CYCLE, 5' RAMP, 10' DWELL	1208	MAX3646ETG+	-65C TO 150C	1000 CYS	77	0	JJR0J3046BA
Total:						0	

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